

# SUB75P03-08-E3-VB Datasheet P-Channel 30-V (D-S) MOSFET

PRODUCT SUMMARY				
V <sub>DS</sub> (V)	R <sub>DS(on)</sub> (Ω)	$R_{DS(on)}$ (Ω) $I_D$ (A) <sup>d</sup> $Q_g$ (Ty		
- 30	0.008 at $V_{GS}$ = - 10 V	- 75	56 nC	
	0.011 at V <sub>GS</sub> = - 4.5 V	- 65	30 110	

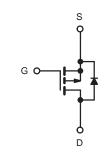
#### **FEATURES**

- Halogen-free
- Trench Power MOSFET
- 100 % R<sub>g</sub> Tested
- 100 % UIS Tested

#### APPLICATIONS

- Load Switch
- Notebook Adaptor Switch





P-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS $T_A =$	25 °C, unless othe	erwise noted		
Parameter	Symbol	Limit	Unit	
Drain-Source Voltage		V <sub>DS</sub>	- 30	V
Gate-Source Voltage		V <sub>GS</sub>	± 20	v
	T <sub>C</sub> = 25 °C		- 75	
Continuous Drain Current (T, = 150 °C)	T <sub>C</sub> = 70 °C		- 65	
$Continuous Drain Current (T_j = 150 C)$	T <sub>A</sub> = 25 °C	I <sub>D</sub>	-55 <sup>a, b</sup>	
	T <sub>A</sub> = 70 °C		-45 <sup>a, b</sup>	•
Pulsed Drain Current		I <sub>DM</sub>	- 200	Α
Continuous Source Drain Diade Current	T <sub>C</sub> = 25 °C		- 4.1	
Continuous Source-Drain Diode Current	T <sub>A</sub> = 25 °C	- <sup>I</sup> s	- 2.2 <sup>a, b</sup>	
Avalanche Current	L = 0.1 mH	I <sub>AS</sub>	- 75	
Single-Pulse Avalanche Energy L = 0.		E <sub>AS</sub>	280	mJ
	T <sub>C</sub> = 25 °C		250	
Manimum Davies Dissis ation	T <sub>C</sub> = 70 °C	р	205	w
Maximum Power Dissipation	T <sub>A</sub> = 25 °C	P <sub>D</sub>	3.7 <sup>a, b</sup>	VV
	T <sub>A</sub> = 70 °C	1	2.7 <sup>a, b</sup>	
Operating Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>stg</sub>	- 55 to 150	°C

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient <sup>a, c</sup>	t ≤ 10 s	R <sub>thJA</sub>	38	46	°C/W	
Maximum Junction-to-Foot	Steady State	R <sub>thJF</sub>	20	25		

Notes:

a. Surface mounted on 1" x 1" FR4 board.

b. t = 10 s.

c. Maximum under Steady State conditions is 85  $^{\circ}\text{C/W}.$ 

d. Based on T<sub>C</sub> = 25 °C.



Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static					-		
Drain-Source Breakdown Voltage	V <sub>DS</sub>	V <sub>GS</sub> = 0 V, I <sub>D</sub> = - 250 μA	- 30			V	
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	/ps/T		- 34		mV/	
V <sub>GS(th)</sub> Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I <sub>D</sub> = - 250 μA		5.3		°C	
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = - 250 μA	- 1.0		- 2.5	V	
Gate-Source Leakage	I <sub>GSS</sub>	$V_{DS} = 0 V, V_{GS} = \pm 25 V$			± 100	nA	
		V <sub>DS</sub> = - 30 V, V <sub>GS</sub> = 0 V			- 1	μΑ	
Zero Gate Voltage Drain Current	IDSS	V <sub>DS</sub> = - 30 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 55 °C			- 5		
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	$V_{DS} \ge -10 \text{ V}, \text{ V}_{GS} = -10 \text{ V}$	- 30			Α	
	-	V <sub>GS</sub> = - 10 V, I <sub>D</sub> = - 10 A		0.008		Ω	
Drain-Source On-State Resistance <sup>a</sup>	R <sub>DS(on)</sub>	V <sub>GS</sub> = - 4.5 V, I <sub>D</sub> = - 8 A		0.011			
Forward Transconductance <sup>a</sup>	9 <sub>fs</sub>	V <sub>DS</sub> = - 10 V, I <sub>D</sub> = - 10 A		28		S	
Dynamic <sup>b</sup>							
Input Capacitance	C <sub>iss</sub>			4550		pF	
Output Capacitance	C <sub>oss</sub>	$V_{DS}$ = - 15 V, $V_{GS}$ = 0 V, f = 1 MHz		1455			
Reverse Transfer Capacitance	C <sub>rss</sub>			570			
Total Gate Charge		$V_{DS}$ = - 15 V, $V_{GS}$ = - 10 V, $I_{D}$ = - 10 A		115			
	$Q_{g} = V_{DS} = -15 \text{ V},  \text{V}_{GS} = -4.5 \text{ V},  \text{I}_{D} = -10 \text{ A}$		56		nC		
Gate-Source Charge			8				
Gate-Drain Charge	$Q_{gd}$			22			
Gate Resistance	R <sub>g</sub>	f = 1 MHz	0.5	2.2	4.4	Ω	
Turn-On Delay Time	t <sub>d(on)</sub>			13	25	-	
Rise Time	t <sub>r</sub>	$V_{DD}$ = - 15 V, $R_L$ = 1.5 $\Omega$		12	24		
Turn-Off DelayTime	t <sub>d(off)</sub>	$\rm I_D \cong$ - 10 A, $\rm V_{GEN}$ = - 10 V, $\rm R_g$ = 1 $\Omega$		40	70		
Fall Time	t <sub>f</sub>			9	18	ns	
Turn-On Delay Time	t <sub>d(on)</sub>			48	80	115	
Rise Time	t <sub>r</sub>	$V_{DD}$ = - 15 V, $R_L$ = 1.5 $\Omega$		92	160	_	
Turn-Off DelayTime	t <sub>d(off)</sub>	$I_D\cong$ - 10 A, $V_{GEN}$ = - 4.5 V, $R_g$ = 1 $\Omega$		34	60		
Fall Time	t <sub>f</sub>			19	35		
Drain-Source Body Diode Characteris	stics						
Continous Source-Drain Diode Current	۱ <sub>s</sub>	T <sub>C</sub> = 25 °C			- 4.1	A	
Pulse Diode Forward Current	I <sub>SM</sub>				- 60		
Body Diode Voltage	V <sub>SD</sub>	I <sub>S</sub> = - 3 A, V <sub>GS</sub> = 0 V		- 0.75	- 1.2	V	
Body Diode Reverse Recovery Time	t <sub>rr</sub>			27	45	ns	
Body Diode Reverse Recovery Charge	harge $Q_{rr}$ $I_F = -10 \text{ A}, \text{ dI/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 \text{ °C}$			16	27	nC	
Reverse Recovery Fall Time	t <sub>a</sub>	$t_a$ $F = -10 \text{ A, unut} = 100 \text{ A/µs, } T_J = 25 ^{\circ}\text{C}$		12		ns	
Reverse Recovery Rise Time	t <sub>b</sub>		15		115		

Notes:

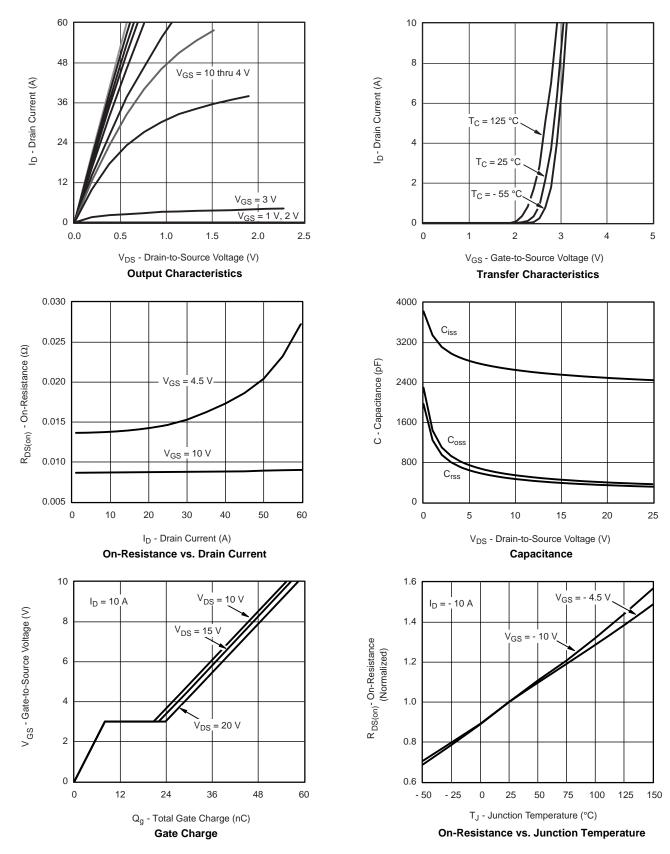
a. Pulse test; pulse width  $\leq$  300  $\mu s,$  duty cycle  $\leq$  2 %.

b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

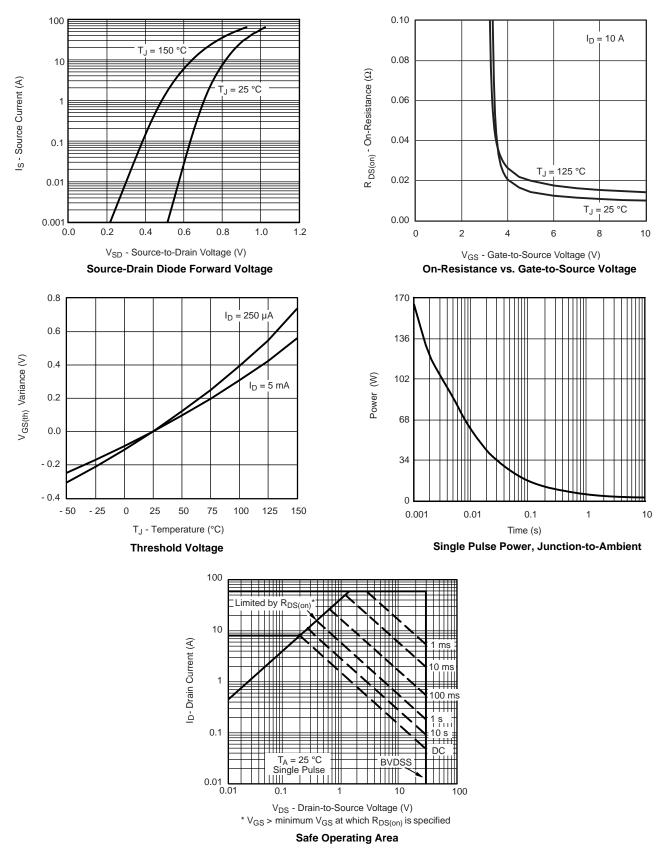






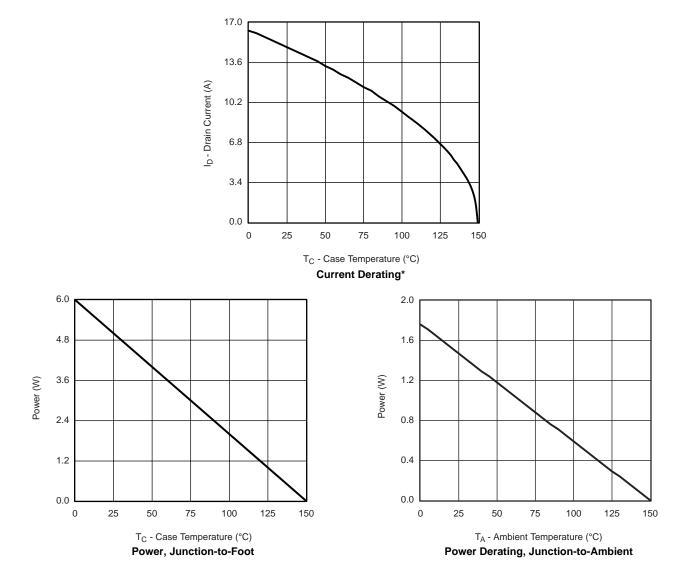


### TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted





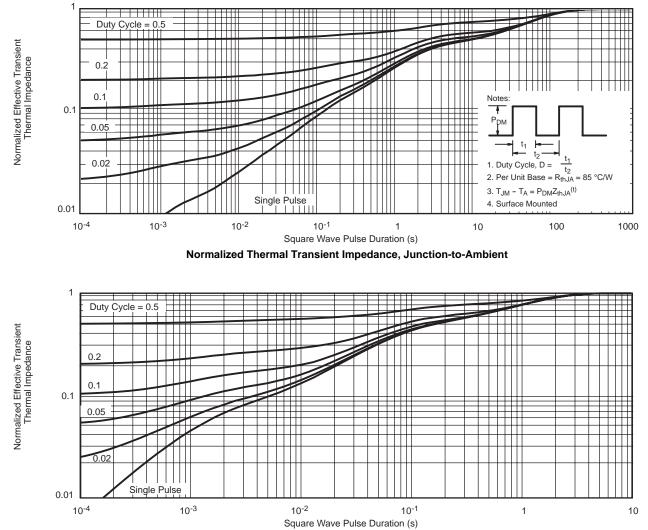
## MOSFET TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



\* The power dissipation  $P_D$  is based on  $T_{J(max)}$  = 150 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.



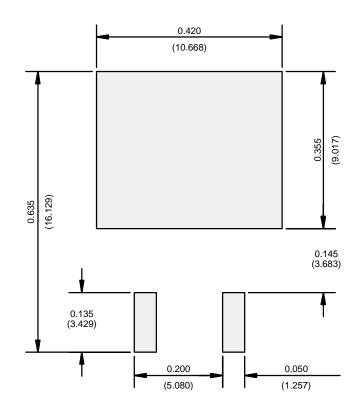
## TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



Normalized Thermal Transient Impedance, Junction-to-Foot



# **RECOMMENDED MINIMUM PADS FOR D<sup>2</sup>PAK: 3-Lead**



Recommended Minimum Pads Dimensions in Inches/(mm)



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